

# MSA-1100 MODAMPTM Cascadable Silicon Bipolar Monolithic Microwave Integrated Circuit Amplifiers

#### **Features**

- High Dynamic Range Cascadable 50  $\Omega$  or 75  $\Omega$  Gain Block
- 3 dB Bandwidth: 50 MHz to 1.6 GHz
- 17.5 dBm Typical P<sub>1dB</sub> at 0.5 GHz
- 12 dB Typical 50 Ω Gain at 0.5 GHz
- 3.5 dB Typical Noise Figure at 0.5 GHz

#### Description

The MSA-1100 is a high performance silicon bipolar Monolithic Microwave Integrated Circuit (MMIC) chip. This MODAMP<sup>TM</sup> MMIC is designed for high dynamic range in either 50 or 75  $\Omega$  systems by combining low noise figure with high IP3. Typical applications include narrow and broadband linear amplifiers in industrial and military applications.

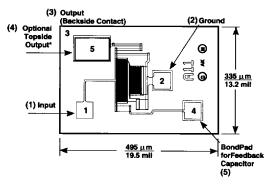
The MODAMP MSA-series is fabricated using a 10 GHz  $f_T$ , 25 GHz  $f_{MAX}$ , silicon bipolar MMIC process which utilizes nitride self-alignment, ion implantation and gold metallization to achieve excellent uniformity, performance and reliability. The use of an external bias resistor for temperature and current stability also allows bias flexibility.

The recommended assembly procedure is gold-eutectic die attach at 400°C and either wedge or ball bonding using 0.7 mil gold wire.

This chip is intended to be used with an external blocking capacitor completing the shunt feedback path (closed loop). Data sheet characterization is given for a 200 pF capacitor. Low frequency performance can be extended by using a larger valued capacitor<sup>1</sup>.

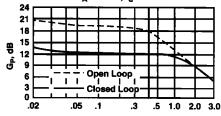
Electrical Specifications<sup>2</sup>, T<sub>A</sub> = 25°C

#### Chip Outline<sup>1</sup>



Unless otherwise specified, tolerances are  $\pm 13~\mu m/\pm 0.5$  mils. Chip thickness is  $114~\mu m/4.5$  mil Bond Pads are  $41~\mu m/1.6$  mil typical on each side. \*Output contact is normally made by die attaching the backside of the die.

# Typical Power Gain vs. Frequency $T_A = 25$ °C, $I_d = 60$ mA



#### Frequency, GHz

Unless otherwise noted, performance is for a MSA-1100 used with an external 200 pF capacitor. See bonding diagram.

Symbol	Parameters and Test Conditions <sup>3</sup> : $I_d$ = 60 mA, $Z_O$ = 50 $\Omega$	<u> </u>	Units	Min.	<b>Typ.</b> 12.5	Max.
G <sub>P</sub>	Power Gain (IS <sub>21</sub> I <sup>2</sup> )	f = 0.1 GHz	dB			
ΔG <sub>P</sub>	Gain Flatness	f = 0.1 to 1.0 GHz	dB		±0.7	
f <sub>3 dB</sub>	3 dB Bandwidth4	-	GHz		1.6	
VSWR	Input VSWR	f = 0.1 to 1.0 GHz			1.7:1	Г
	Output VSWR	f = 0.1 to 1.0 GHz			1.9:1	
P <sub>1 dB</sub>	Output Power @ 1 dB Gain Compression	f = 0.5 GHz	dBm		17.5	
NF	50 Ω Noise Figure	f = 0.5 GHz	dB		3.5	
IP <sub>3</sub>	Third Order Intercept Point	f = 0.5 GHz	dBm		30.0	
t <sub>D</sub>	Group Delay	f = 0.5 GHz	psec.		125	
V <sub>d</sub>	Device Voltage	-	V	4.5	5.5	6.5
dV/dT	Device Voltage Temperature Coefficient		mV/°C		-8.0	

- Notes: 1. See Application Note, AN-S009: MODAMPTM Silicon MMIC Chip Use for additional information.
  - The recommended operating current range for this device is 40 to 75 mA. Typical performance as a function of current is on the following page
     RF performance of the chip is determined by packaging and testing 10 devices per wafer.
  - Referenced from 0.05 GHz gain (G<sub>P</sub>).

### **Absolute Maximum Ratings**

Parameter	Absolute Maximum <sup>1</sup>
Device Current	100 mA
Power Dissipation <sup>2, 3</sup>	650 mW
RF Input Power	+13 dBm
Junction Temperature	200°C
Storage Temperature	-65 to 200°C

Thermal	Resistance <sup>2,4</sup> :	A. 2	- 57°C/W
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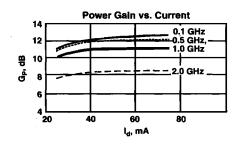
#### Notes:

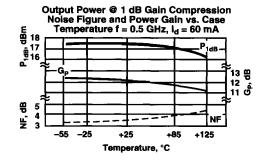
- 1. Permanent damage may occur if any of these limits are exceeded.
- 2. TMOUNTING SURFACE = 25°C.
  3. Derate at 17.5 mW/°C for TMOUNTING SURFACE > 163°C.
- The small spot size of the technique used results in a higher, though more accurate, determination of  $\theta_{ic}$  than do alternate methods.

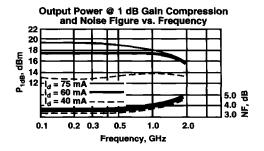
# Typical Performance, $T_A = 25^{\circ}C$

(Unless otherwise noted)

Note: Unless otherwise noted, performance is for a MSA-1100 used with an external 200 pF capacitor. See bonding diagram.





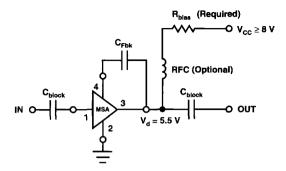


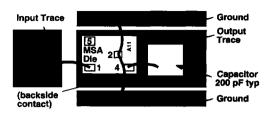
#### **Part Number Ordering Information**

Part Number	Devices Per Tray				
MSA-1100-GP2	10				
MSA-1100-GP4	100				
MSA-1100-GP6	Up to 300				

# **Typical Biasing Configuration**

# **Bonding Diagram**





Numbers refer to pin contacts listed on the Chip Outline.

Typical Scattering Parame			eters <sup>5,6</sup> S <sub>21</sub>			S <sub>12</sub>			T <sub>A</sub> = 25°C, I <sub>d</sub> = 60 mA S <sub>22</sub>		
GHz	Mag	Ang	dB	Mag	Ang	dB	Mag	Ang	Mag	Ang	k
.001	.72	-26	19.3	9.23	168	-23.4	.067	46	.72	-27	.52
.005	.19	-73	14.1	5.09	165	-16.7	.147	11	.19	-77	.96
.010	.16	-69	13.9	4.97	168	-16.6	.148	9	.16	-79	.99
.050	.04	-59	12.8	4.39	175	-16.0	.159	3	.04	-102	1.06
.100	.05	-66	12.8	4.38	175	-16.0	.158	2	.05	-100	1.06
.200	.07	-78	12.8	4.36	170	-15.9	.161	4	.08	-100	1.05
.400	.14	-92	12.7	4.31	162	-15.6	.165	7	.14	-105	1.01
.600	.19	-102	12.5	4.22	153	-15.3	.171	10	.21	-111	.96
.800	.25	-110	12.3	4.11	144	-14.9	.180	13	.27	-116	.90
1.000	.31	-117	12.0	4.00	137	-14.4	.190	14	.33	-122	.83
1.500	.40	-132	10.9	3.52	117	-13.4	.214	15	.42	-136	.70
2.000	.47	-145	9.6	3.01	100	-12.6	.235	14	.46	-148	.64
2.500	.50	-150	8.3	2.60	89	-12.0	.251	16	.45	-152	.63
3.000	.52	-158	7.0	2.23	77	-11.6	.263	17	.42	-156	.66
3.500	.51	-164	5.7	1.92	68	-11.1	.278	19	.38	-155	.73
4.000	.50	-169	4.6	1.70	61	-10.5	.297	22	.34	-152	.79

Notes: 5. S-parameters are de-embedded from 200 mil BeO package measured data using the package model found in the DEVICE MODELS section.
6. S-parameter data assumes an external 200 pF capacitor. Low frequency performance can be exended using a larger valued capacitor.